

<b>Notice of References Cited</b>	Application/Control No. 10/544,193		Applicant(s)/Patent Under Reexamination HEZEMANS ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,838,515 A	11-1998	Mortazavi et al.	360/78.12
*	B	US-6,034,499 A	03-2000	Tranovich, Stephen J.	318/650
*	C	US-2001/0019526 A1	09-2001	Takeda, Kunio	369/75.2
*	D	US-2002/0044520 A1	04-2002	Kabasawa, Hidetoshi	369/77.2
*	E	US-6,434,087 B1	08-2002	Schell et al.	369/13.02
*	F	US-2003/0053381 A1	03-2003	Takahashi et al.	369/30.24
*	G	US-2003/0174617 A1	09-2003	Kim et al.	369/53.22
*	H	US-2004/0066712 A1	04-2004	Mitsumoto et al.	369/030.36
*	I	US-2005/0204373 A1	09-2005	Ueno et al.	720/616
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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